Francesco Cazzaniga was born in 1968. He received the degree in physics from Milano University, Milan, Italy, in 1994. In 1995, he joined STMicroelectonics, where he was engaged in research on atomic force microscopy characterization. In 1998, he started to specialize in TEM sample preparation with FIB. He is currently in charge of a Failure Analysis group. His expertise is in the application of focused ion beam for physical failure analysis, especially for TEM sample preparation. He is member of the ST Technical Staff.